

Detection Isn't the Problem. Decisions Are.

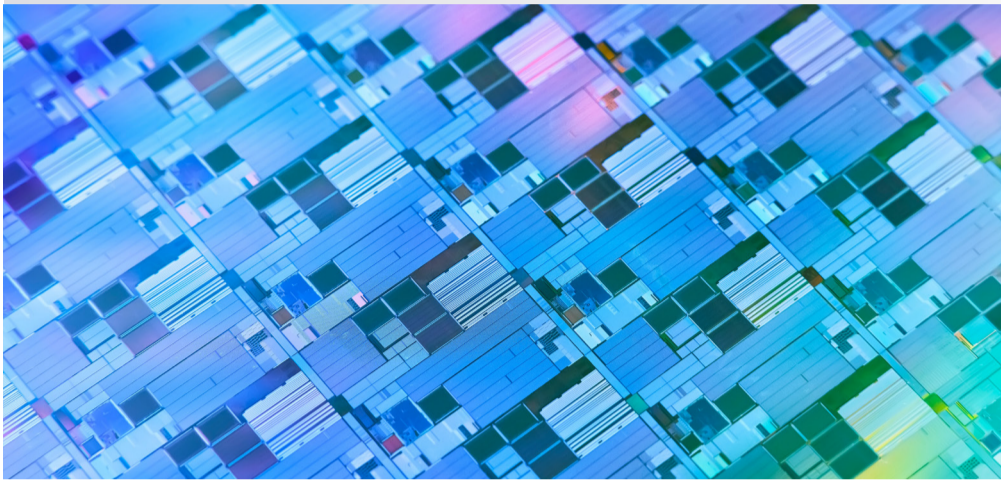


THE SITUATION

Rising cost. Rising complexity. Rising pressure on yield.

>€12,800

Cost per advanced-node wafer¹



Automotive & power devices

Near-zero defect tolerance and long qualification cycles

Heterogeneous integration

Multiple high-value dies → single package

Hybrid bonding <10µm pitch

Single particles can cause bonding failure

Multi-die stacking

Each additional layer increases yield sensitivity



For semiconductor equipment OEMs, tool value increasingly depends on decision capability

¹ <https://siliconanalysts.com/guide/semiconductor-costs>

THE SHIFT

As costs rise, yield shifts to the tool-level

As wafers move through each process step:



Value increases

+



Defect cost increases



Late decisions = expensive scrap

Yield is now shaped earlier, inside the process:

- From final test → to in-process decisions
- From inspection → to action
- From detection → to yield impact

Tools are now measured by:

- Impact on yield outcomes
- Not just process execution

WHERE IT BREAKS

Detection is not the bottleneck. Disposition is.

Many process tools already identify anomalies early. The issue:

- Inconsistent classification
- Delayed disposition decisions
- Tools unable to act on the data they already capture

The result: process visibility without process-level decision capability

THE COST

Classification ambiguity limits tool-level value

Uncertain classification leads to:

- Conservative customer process settings
- Preventable downstream failures
- Reduced customer confidence at critical process steps
- Yield impact tied directly to tool decisions

At production scale, small errors become measurable yield loss

THE GAP

Where value is lost



- Process tools increasingly capture relevant data
- Inspection systems flag anomalies
- Relevant data already exists

But it is not converted into decisions. What is missing:

- Real-time classification
- Immediate disposition
- Decisions at source

When this gap is closed, tools become active contributors to yield performance

THE OEM IMPACT

Unlocking measurable outcomes

When a tool supports yield improvement:



Increased production value
A more central role within the customer process flow



Stronger tool value
Measured by contribution to customer yield, not just process step



Competitive advantage
Built-in decision capability that competitors do not offer